

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/617,055	LEE ET AL.	
Examiner	Art Unit	
Emeka Ebirim	2166	

	SEARCHED		
Class	Subclass	Date	Examiner
Updated	Updated	7/20/2006	EE
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST search	7/20/2006	EE
Consulted Pham Khanh (primary)	7/20/2006	EE
Google Scholar	7/20/2006	EE
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Se	arch No	les

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